

<b>Notice of References Cited</b>	Application/Control No. 10/651,062	Applicant(s)/Patent Under Reexamination AOKI ET AL.	
	Examiner Christopher M. Keehan	Art Unit 1712	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,294,313 B1	09-2001	Kobayashi et al.	430/302
	B	US-6,228,480 B1	05-2001	Kimura et al.	428/328
	C	US-			
	D	US-			
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	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	EP 0633064 A1	01-1995	JP	Murasawa et al.	
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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